	INTERNATIONAL SEARCH REPOR	PCT/GB 03	/02599				
A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01R31/3167 G01R31/3183							
According to International Patent Classification (IPC) or to both national classification and IPC B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) IPC 7 G01R							
Documentation searched other than minimum documentation to the extent that such documents are included. In the fields searched							
Electronic data base consulted during the international search (name of data base and, where practical, search terms used) EPO-Internal, INSPEC, WPI Data, IBM-TDB							
C. DOCUME	ENTS CONSIDERED TO BE RELEVANT						
Category °	Citation of document, with indication, where appropriate, of the rele	Relevant to claim No.					
Х	ZHENG H H ET AL: "A novel test g approach for parametric faults in analog circuits" PROCEEDINGS. 14TH IEEE VLSI TEST (CAT. NO.96TB100043), PROCEEDINGS VLSI TEST SYMPOSIUM, PRINCETON, N 28 APRIL-1 MAY 1996, pages 470-475, XP002265465 1996, Los Alamitos, CA, USA, IEEE	1-14, 16-34, 47-50					
Y	Soc. Press, USA ISBN: 0-8186-7304-4 page 471, column 1, paragraph 2 - column 2, paragraph 1; figures 2-	page 473,	22				
X Furt	her documents are listed in the continuation of box C.	X Patent family members are listed	i in annex.				
"A" docum conside "E" earlier ifiling of "L" docum which citatio "O" docum of there." "P" docum later the state of the	ternational filing date h the application but heory underlying the claimed invention of be considered to focument is taken alone claimed invention niventive step when the nore other such docu- ous to a person skilled it family tarch report						
2	0 April 2004	ı 1, 1 . 05. 200	4				
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk Tel. (+31–70) 340–2040, Tx. 31 651 epo nl, Fax: (+31–70) 340–3016		Authorized officer Böhm-Pélissier,					

INTERNATIONAL SEARCH REPORT PCT/GB 03/02599 C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT Category ° Citation of document, with indication, where appropriate, of the relevant passages Relevant to claim No. SAAB D G ET AL: "CRIS: A test cultivation Υ 22 program for sequential VLSI circuits" PROCEEDINGS OF THE IEEE/ACM INTERNATIONAL CONFERENCE ON COMPUTER AIDEDDESIGN (1CCAD). SANTA CLARA, NOV. 8 - 12, 1992, LOS ALAMITOS, IEEE COMP. SOC. PRESS, US, vol. CONF. 10,. 8 November 1992 (1992-11-08), pages 216-219, XP010094549 ISBN: 0-8186-3010-8 page 217, column 1 X VAN SPAANDONK J ET AL: "SELECTING 1-14,16,20,23, MEASUREMENTS TO TEST THE FUNCTIONAL BEHAVIOR OF ANALOG CIRCUITS" 24,47,48 JOURNAL OF ELECTRONIC TESTING, KLUWER ACADEMIC PUBLISHERS, DORDRECHT, NL. vol. 9, no. 1/2, 1 August 1996 (1996-08-01), pages 9-18, XP000636621 ISSN: 0923-8174 page 15 -page 16 X BALIVADA A ET AL: "A UNIFIED APPROACH FOR 1,2,16, FAULT SIMULATION OF LINEAR MIXED-SIGNAL 20,23, CIRCUITS" 24,47,48 JOURNAL OF ELECTRONIC TESTING, KLUWER ACADEMIC PUBLISHERS, DORDRECHT, NL. vol. 9, no. 1/2, 1 August 1996 (1996-08-01), pages 29-41, XP000636623 ISSN: 0923-8174 page 33, column 2, paragraph 2 -page 35; figures 6,11; table 3 Α WO 98/55880 A (SAAB KHALED ; HAMIDA NAIM 1 - 34. BEN (US); KAMINSKA BOZENA (US); OPMAXX IN) 47-50 10 December 1998 (1998-12-10) abstract; figures 7,8,11,13 X US 5 745 409 A (SO HOCK C ET AL) 35-46. 28 April 1998 (1998-04-28) 51-55 abstract; figures 1,3A column 3, line 18 - line 50 column 8, line 34 -column 9, line 5 Α US 5 694 356 A (SO HOCK C ET AL) 35-46. 2 December 1997 (1997-12-02) 51-55 abstract; figure 29 X US 5 748 124 A (WHYTE ROBERT ET AL) 35,42, 5 May 1998 (1998-05-05) 51,53,55 abstract; figure 1

Form PCT/ISA/210 (continuation of second sheet) (January 2004)

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0.40	L DOCUMENTO COMPLETE DE LA CASA DEL CASA DE LA CASA DEL CASA DE LA	FC1/6B 03/02599
	on) DOCUMENTS CONSIDERED TO BE RELEVANT	
Category * (Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
4	US 5 793 778 A (QURESHI FAZAL UR REHMAN) 11 August 1998 (1998-08-11) abstract; figure 1	35-46, 51-55
	(continuation of second short) (proper 2004)	

INTERNATIONAL SEARCH REPORT

	Informat	tion on patent family mer	nbers		PCT/GB	03/02599
Patent document cited in search report		Publication date		Patent tamily member(s)		Publication date
WO 9855880	A	10-12-1998	CA AU CA WO	2206738 7634598 2269914 9855880	3 A 1 A1	02-12-1998 21-12-1998 10-12-1998 10-12-1998
US 5745409	Α	28-04-1998	US US	5815425 5801980		29-09-1998 01-09-1998
US 5694356	А	02-12-1997 ·	JP JP WO US US	10513299 3365779 9614638 5687119 5751639 5638320	B2 B A1 B A B A	15-12-1998 14-01-2003 17-05-1996 11-11-1997 12-05-1998 10-06-1997
US 5748124	А	05-05-1998	US DE FR JP	564652 1963100! 273757! 9189750	A1 A1	08-07-1997 06-02-1997 07-02-1997 22-07-1997
US 5793778	A	11-08-1998	DE	19744818	3 A1	22-10-1998

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Box I Observations where certain claims were found unsearchable (Continuation of item 1 of first sheet)				
This International Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:				
Claims Nos.: because they relate to subject matter not required to be searched by this Authority, namely:				
2. Claims Nos.: because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:				
3. Claims Nos.: because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).				
Box II Observations where unity of invention is lacking (Continuation of item 2 of first sheet)				
This International Searching Authority found multiple inventions in this international application, as follows:				
see additional sheet				
1. X As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.				
2. As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.				
3. As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:				
4. No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:				
Remark on Protest The additional search fees were accompanied by the applicant's protest. X No protest accompanied the payment of additional search fees.				

FURTHER INFORMATION CONTINUED FROM PCT/ISAV 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. Claims: 1-34,47-50

These claims are related to a method/apparatus for generating digital test inputs for an analog circuit by using an optimisation algorithm.

2. Claims: 35-46, 51-55

These claims relate to a method/apparatus for testing an analog circuit by means of an optimised digital input signal for determining a fault.